

Notice of References Cited

Application/Control No.

10/517,493

Applicant(s)/Patent Under
Reexamination
TOTSUKA ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 1 of 6

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Applicant(s)/Patent Under
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TOTSUKA ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 2 of 6

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Application/Control No.

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Applicant(s)/Patent Under
Reexamination
TOTSUKA ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 3 of 6

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Application/Control No.

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Applicant(s)/Patent Under
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TOTSUKA ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 4 of 6

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Application/Control No.

10/517,493

Applicant(s)/Patent Under
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TOTSUKA ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 5 of 6

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TOTSUKA ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 6 of 6

U.S. PATENT DOCUMENTS

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